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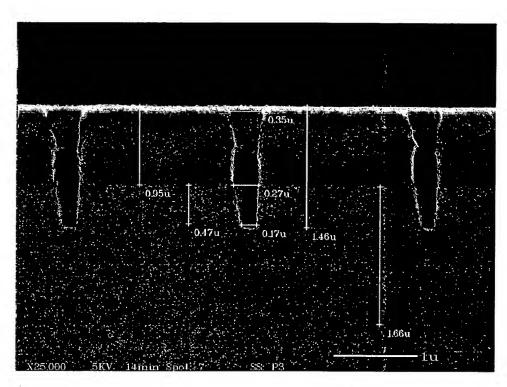
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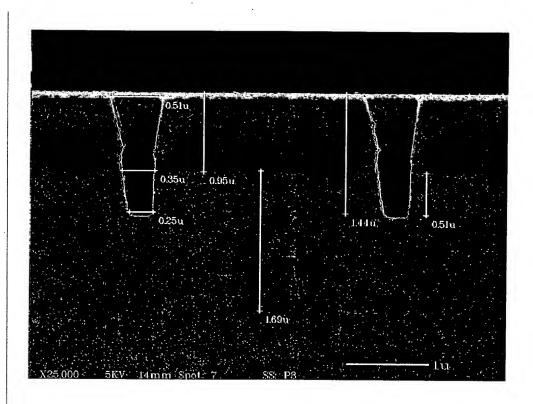
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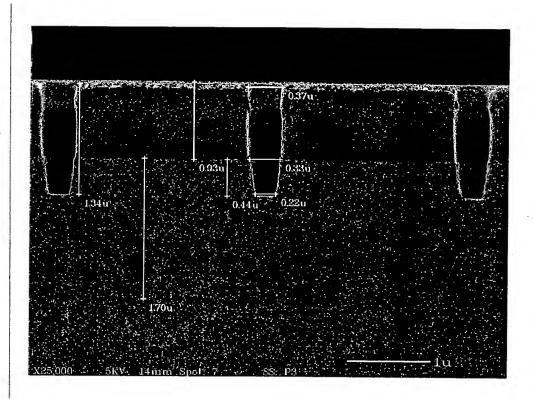
SEM image of 0.35 micron via etch with FTM/C $_4\mathbb{F}_6$ /Ar plasma

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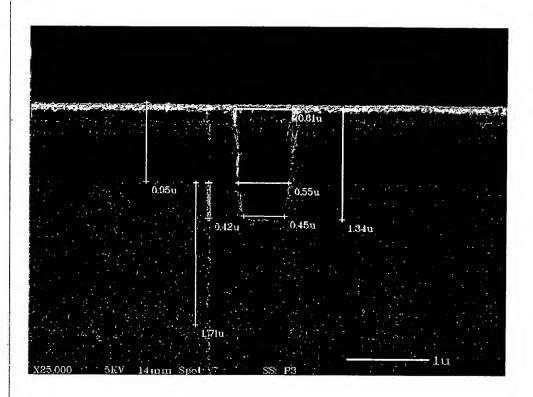
SEM image of 0.50 micron via etch with FTM/C $_4$ F $_6$ /Ar plasma

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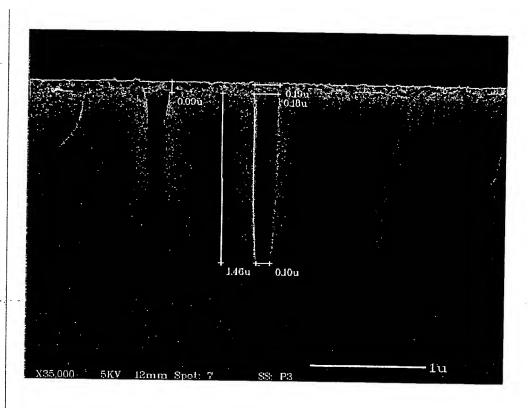
SEM image of 0.35 micron via etch with $O_2/C_4F_6/Ar$ plasma

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SEM image of 0.50 micron via etch with $O_2/C_4F_6/Ar$ plasma

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SEM image of 0.30 micron via etch with FTM/C $_4$ F $_6$ /Ar Mixture



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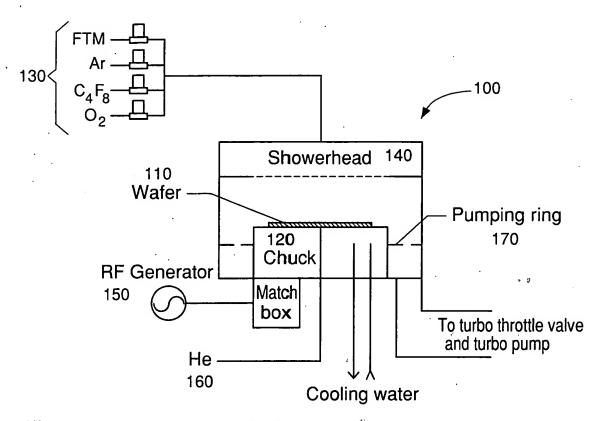


Figure 1

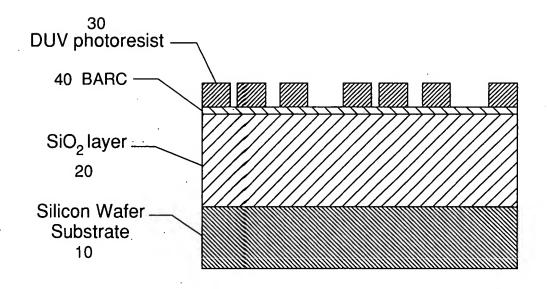


Figure 2